## $32 \mathrm{~K} \times 16$ Static RAM

## Features

- 3.3V operation (3.0V-3.6V)
- High speed
$-\mathrm{t}_{\mathrm{AA}}=10 \mathrm{~ns}$
- Low active power
— 540 mW (max., 12 ns )
- Very Low standby power
— $330 \mu \mathrm{~W}$ (max., "L" version)
- Automatic power-down when deselected
- Independent Control of Upper and Lower bytes
- Available in 44-pin TSOP II and 400-mil SOJ


## Functional Description

The CY7C1020V is a high-performance CMOS static RAM organized as 32,768 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.
Writing to the device is accomplished by taking chip enable ( $\overline{C E}$ ) and write enable ( $\overline{W E}$ ) inputs LOW. If byte low enable
(BLE) is LOW, then data from I/O pins $\left(1 / O_{1}\right.$ through $\left.I / O_{8}\right)$, is written into the location specified on the address pins ( $\mathrm{A}_{0}$ through $\mathrm{A}_{14}$ ). If byte high enable ( $\overline{\mathrm{BHE})}$ is LOW, then data from $\mathrm{I} / \mathrm{O}$ pins $\left(\mathrm{I} / \mathrm{O}_{9}\right.$ through $\left.\mathrm{I} / \mathrm{O}_{16}\right)$ is written into the location specified on the address pins ( $\mathrm{A}_{0}$ through $\mathrm{A}_{14}$ ).
Reading from the device is accomplished by taking chip enable ( $\overline{\mathrm{CE}}$ ) and output enable ( $\overline{\mathrm{OE})}$ LOW while forcing the write enable (WE) HIGH. If byte low enable ( $\overline{\mathrm{BLE}}$ ) is LOW, then data from the memory location specified by the address pins will appear on $\mathrm{I} / \mathrm{O}_{1}$ to $\mathrm{I} / \mathrm{O}_{8}$. If byte high enable ( $\left.\overline{\mathrm{BHE}}\right)$ is LOW , then data from memory will appear on $\mathrm{I} / \mathrm{O}_{9}$ to $\mathrm{I} / \mathrm{O}_{16}$. See the truth table at the back of this datasheet for a complete description of read and write modes.
The input/output pins ( $I / \mathrm{O}_{1}$ through $\mathrm{I} / \mathrm{O}_{16}$ ) are placed in a high-impedance state when the device is deselected ( $\overline{\mathrm{CE}}$ HIGH), the outputs are disabled ( $\overline{O E}$ HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or during a write operation (CE LOW, and WE LOW).
The CY7C1020V is available in standard 44-pin TSOP type II and 400-mil-wide SOJ packages.


## Selection Guide

|  |  | 7C1020V-10 | 7C1020V-12 | 7C1020V-15 | 7C1020V-20 |
| :--- | :---: | :---: | :---: | :---: | :---: |
| Maximum Access Time (ns) | 10 | 12 | 15 | 20 |  |
| Maximum Operating Current (mA) |  | 130 | 120 | 110 | 100 |
|  | L | 100 | 90 | 80 | 70 |
| Maximum CMOS Standby Current (mA) |  | 1 | 1 | 1 | 1 |
|  | L | 0.1 | 0.1 | 0.1 | 0.1 |

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)
Storage Temperature $\qquad$ $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Ambient Temperature with
Power Applied $\qquad$ .$-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ Supply Voltage on $\mathrm{V}_{\mathrm{CC}}$ to Relative $\mathrm{GND}^{[1]} \ldots .-0.5 \mathrm{~V}$ to +4.6 V DC Voltage Applied to Outputs in High Z State ${ }^{[1]}$ -0.5 V to $\mathrm{V}_{\mathrm{Cc}}+0.5 \mathrm{~V}$
DC Input Voltage ${ }^{[1]}$ $\qquad$

$$
.-0.5 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{Cc}}+0.5 \mathrm{~V}
$$

Current into Outputs (LOW)......................................... 20 mA
Static Discharge Voltage >2001V (per MIL-STD-883, Method 3015) Latch-Up Current $\qquad$ >200 mA

Operating Range

| Range | Ambient <br> Temperature${ }^{[2]}$ |
| :--- | :---: | :---: |$\quad$ V $_{\text {CC }}$.

Electrical Characteristics Over the Operating Range


## Notes:

1. $\mathrm{V}_{\mathrm{IL}}$ (min.) $=-2.0 \mathrm{~V}$ for pulse durations of less than 20 ns .
2. $\mathrm{T}_{\mathrm{A}}$ is the "instant on" case temperature.

Electrical Characteristics Over the Operating Range (continued)

| Parameter | Description | Test Conditions |  | 7C1020V-15 |  | 7C1020V-20 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | Min. | Max. | Min. | Max. |  |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | $\mathrm{V}_{\mathrm{CC}}=$ Min., $\mathrm{I}_{\mathrm{OH}}=-4$. |  | 2.4 |  | 2.4 |  | V |
| $\mathrm{V}_{\mathrm{OL}}$ | Output LOW Voltage | $\mathrm{V}_{\mathrm{CC}}=$ Min., $\mathrm{I}_{\mathrm{OL}}=8.0$ |  |  | 0.4 |  | 0.4 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage |  |  | 2.0 | $\begin{gathered} \mathrm{V}_{\mathrm{CC}}+ \\ 0.3 \mathrm{~V} \end{gathered}$ | 2.0 | $\begin{gathered} \mathrm{V}_{\mathrm{CC}}+ \\ 0.3 \mathrm{~V} \end{gathered}$ | V |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage ${ }^{[1]}$ |  |  | -0.5 | 0.8 | -0.5 | 0.8 | V |
| IIX | Input Load Current | $\mathrm{GND} \leq \mathrm{V}_{1} \leq \mathrm{V}_{\mathrm{CC}}$ |  | -1 | +1 | -1 | +1 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{OZ}}$ | Output Leakage Current | GND $\leq \mathrm{V}_{1} \leq \mathrm{V}_{\mathrm{CC}}$, Output Disabled |  | -2 | +2 | -2 | +2 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{CC}}$ | $\mathrm{V}_{\text {CC }}$ Operating Supply Current | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}=\mathrm{Max} . \\ & \mathrm{l}_{\mathrm{OUT}}=0 \mathrm{~mA}, \\ & \mathrm{f}=\mathrm{f}_{\mathrm{MAX}}=1 / \mathrm{t}_{\mathrm{RC}} \end{aligned}$ |  |  | 110 |  | 100 | mA |
|  |  |  | L |  | 80 |  | 70 | mA |
| $\mathrm{I}_{\text {SB1 }}$ | Automatic CE Power-Down Current —TTL Inputs | $\begin{aligned} & \text { Max. } V_{\text {CC }}, C E \geq V_{\text {IH }} \\ & V_{\text {IN }} \geq V_{\text {IH }} \text { or } \\ & V_{\text {IN }} \leq V_{\text {IL }}, f=f_{\text {MAX }} \end{aligned}$ |  |  | 15 |  | 15 | mA |
|  |  |  | L |  | 7 |  | 7 | mA |
| $\mathrm{I}_{\text {SB2 }}$ | Automatic CE Power-Down Current -CMOS Inputs | $\begin{aligned} & \text { Max. } V_{C C}, \\ & C E \geq V_{C C}-0.3 V, \\ & V_{I N} \geq V_{C C}-0.3 V, \\ & \text { or } V_{I N} \leq 0.3 V, f=0 \end{aligned}$ |  |  | 1 |  | 1 | mA |
|  |  |  | L |  | 100 |  | 100 | $\mu \mathrm{A}$ |

Capacitance ${ }^{[3]}$

| Parameter | Description | Test Conditions | Max. | Unit |
| :--- | :--- | :--- | :---: | :---: |
| $\mathrm{C}_{\mathrm{IN}}$ | Input Capacitance | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{f}=1 \mathrm{MHz}$, | 8 | pF |
| $\mathrm{C}_{\mathrm{OUT}}$ | Output Capacitance | $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}$ | 8 | pF |

Notes:
3. Tested initially and after any design or process changes that may affect these parameters.

## AC Test Loads and Waveforms



Switching Characteristics ${ }^{[4]}$ Over the Operating Range

| Parameter | Description | 7C1020V-10 |  | 7C1020V-12 |  | 7C1020V-15 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Max. | Min. | Max. | Min. | Max. |  |
| READ CYCLE |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{RC}}$ | Read Cycle Time | 10 |  | 12 |  | 15 |  | ns |
| $\mathrm{t}_{\mathrm{AA}}$ | Address to Data Valid |  | 10 |  | 12 |  | 15 | ns |
| $\mathrm{t}_{\mathrm{OHA}}$ | Data Hold from Address Change | 3 |  | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {ACE }}$ | CE LOW to Data Valid |  | 10 |  | 12 |  | 15 | ns |
| $\mathrm{t}_{\text {DOE }}$ | $\overline{\text { OE LOW to Data Valid }}$ |  | 5 |  | 6 |  | 7 | ns |
| t LZOE | OE LOW to Low Z | 0 |  | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\text {Hzoe }}$ | $\overline{\text { OE HIGH to High } Z^{[5, ~ 6] ~}}$ |  | 5 |  | 6 |  | 7 | ns |
| tlzce | CE LOW to Low ${ }^{[6]}$ | 3 |  | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {HZCE }}$ | CE HIGH to High $\mathbf{Z}^{[5,6]}$ |  | 5 |  | 6 |  | 7 | ns |
| $\mathrm{t}_{\text {PU }}$ | CE LOW to Power-Up | 0 |  | 0 |  | 0 |  | ns |
| $t_{\text {PD }}$ | CE HIGH to Power-Down |  | 12 |  | 12 |  | 15 | ns |
| $\mathrm{t}_{\text {Dbe }}$ | Byte enable to Data Valid |  | 5 |  | 6 |  | 7 | ns |
| $\mathrm{t}_{\text {LZBE }}$ | Byte enable to Low Z | 0 |  | 0 |  | 0 |  | ns |
| $t_{\text {HZBE }}$ | Byte disable to High Z |  | 5 |  | 6 |  | 7 | ns |
| WRITE CYCLE ${ }^{[7]}$ |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{wc}}$ | Write Cycle Time | 10 |  | 12 |  | 15 |  | ns |
| $\mathrm{t}_{\text {SCE }}$ | CE LOW to Write End | 8 |  | 9 |  | 10 |  | ns |
| $\mathrm{t}_{\text {AW }}$ | Address Set-Up to Write End | 7 |  | 8 |  | 10 |  | ns |
| $\mathrm{t}_{\mathrm{HA}}$ | Address Hold from Write End | 0 |  | 0 |  | 0 |  | ns |
| $t_{\text {SA }}$ | Address Set-Up to Write Start | 0 |  | 0 |  | 0 |  | ns |
| $t_{\text {PWE }}$ | WE Pulse Width | 7 |  | 8 |  | 10 |  | ns |
| $\mathrm{t}_{\text {SD }}$ | Data Set-Up to Write End | 5 |  | 6 |  | 10 |  | ns |
| $\mathrm{t}_{\mathrm{HD}}$ | Data Hold from Write End | 0 |  | 0 |  | 0 |  | ns |
| tlzwe | WE HIGH to Low ${ }^{[6]}$ | 3 |  | 3 |  | 3 |  | ns |
| $\mathrm{t}_{\text {HZWE }}$ | WE LOW to High $\mathrm{Z}^{[5,6]}$ |  | 5 |  | 6 |  | 7 | ns |
| $\mathrm{t}_{\mathrm{BW}}$ | Byte enable to end of write | 7 |  | 8 |  | 9 |  | ns |

## Notes:

4. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V , input pulse levels of 0 to 3.0 V , and output loading of the specified $\mathrm{IOL}_{\mathrm{OL}} / \mathrm{l}_{\mathrm{OH}}$ and 30-pF load capacitance.
5. $t_{H Z O E}, t_{H Z B E}, t_{H Z C E}$, and $t_{H Z W E}$ are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured $\pm 500 \mathrm{mV}$ from steady-state voltage.
6. At any given temperature and voltage condition, $t_{H Z C E}$ is less than $t_{\text {LZCE }}, t_{H Z O E}$ is less than $t_{L Z O E}$, and $t_{H Z W E}$ is less than $t_{Z Z W E}$ for any given device.
7. The internal write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE / BLE LOW. CE, WE and BHE / BLE must be LOW to initiate a write, and the transition of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.

Switching Characteristics ${ }^{[4]}$ Over the Operating Range (continued)

| Parameter | Description | 7C1020V-20 |  | Unit |
| :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Max. |  |
| READ CYCLE |  |  |  |  |
| $\mathrm{t}_{\mathrm{RC}}$ | Read Cycle Time | 20 |  | ns |
| $\mathrm{t}_{\mathrm{AA}}$ | Address to Data Valid |  | 20 | ns |
| $\mathrm{t}_{\text {OHA }}$ | Data Hold from Address Change | 3 |  | ns |
| $\mathrm{t}_{\text {ACE }}$ | $\overline{\text { CE LOW to Data Valid }}$ |  | 20 | ns |
| $\mathrm{t}_{\text {DOE }}$ | OE LOW to Data Valid |  | 9 | ns |
| tlzoe | OE LOW to Low Z | 0 |  | ns |
| t LZCE | $\overline{\text { CE LOW }}$ to Low ${ }^{[6]}$ | 3 |  | ns |
| $\mathrm{t}_{\text {HZCE }}$ | CE HIGH to High ${ }^{[5,6]}$ |  | 9 | ns |
| $\mathrm{t}_{\text {PU }}$ | CE LOW to Power-Up | 0 |  | ns |
| $\mathrm{t}_{\mathrm{PD}}$ | $\overline{\text { CE HIGH to Power-Down }}$ |  | 20 | ns |
| $\mathrm{t}_{\text {DBE }}$ | Byte enable to Data Valid |  | 9 | ns |
| tlzbe | Byte enable to Low Z | 0 |  | ns |
| $t_{\text {HZBE }}$ | Byte disable to High Z |  | 9 | ns |

WRITE CYCLE ${ }^{[7]}$

| $\mathrm{t}_{\text {WC }}$ | Write Cycle Time | 20 | ns |  |
| :--- | :--- | :---: | :---: | :---: |
| $\mathrm{t}_{\text {SCE }}$ | CE LOW to Write End | 12 |  | ns |
| $\mathrm{t}_{\text {AW }}$ | Address Set-Up to Write End | 12 |  | ns |
| $\mathrm{t}_{\text {HA }}$ | Address Hold from Write End | 0 | ns |  |
| $\mathrm{t}_{\text {SA }}$ | Address Set-Up to Write Start | 0 | ns |  |
| $\mathrm{t}_{\text {PWE }}$ | WE Pulse Width | 12 |  | ns |
| $\mathrm{t}_{\text {SD }}$ | Data Set-Up to Write End | 10 |  | ns |
| $\mathrm{t}_{\text {HD }}$ | Data Hold from Write End | 0 | ns |  |
| $\mathrm{t}_{\text {LZWE }}$ | WE HIGH to Low Z $^{[6]}$ | 3 | ns |  |
| $\mathrm{t}_{\text {HZWE }}$ | WE LOW to High Z ${ }^{[5,6]}$ |  | ns |  |
| $\mathrm{t}_{\text {BW }}$ | Byte enable to end of write |  | ns |  |

## Switching Waveforms

## Read Cycle No. $1^{[8,9]}$



## Notes:

8. Device is continuously selected. $\overline{\mathrm{OE}}, \overline{\mathrm{CE}}, \overline{\mathrm{BHE}}$, and/or $\overline{\mathrm{BHE}}=\mathrm{V}_{\mathrm{IL}}$
9. WE is HIGH for read cycle.

Switching Waveforms (continued)
Read Cycle No. 2 ( OE Controlled) ${ }^{[9,10]}$


Write Cycle No. 1 (CE Controlled) ${ }^{[11,12]}$


## Notes:

10. Address valid prior to or coincident with CE transition LOW.
11. Data $\mathrm{I} / \mathrm{O}$ is high impedance if OE or BHE and/or $\mathrm{BLE}=\mathrm{V}_{I H}$.
12. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

Switching Waveforms (continued)
Write Cycle No. 2 (BLE or BHE Controlled)


Write Cycle No. 3 (WE Controlled, OE LOW)


## Truth Table

| CE | OE | WE | BLE | BHE | $\mathrm{l} / \mathrm{O}_{1}-1 / \mathrm{O}_{8}$ | $\mathrm{l} / \mathrm{O}_{9}-\mathrm{l} / \mathrm{O}_{16}$ | Mode | Power |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| H | X | X | X | X | High Z | High Z | Power-Down | Standby ( $\mathrm{ISB}^{\text {) }}$ |
| L | L | H | L | L | Data Out | Data Out | Read - All bits | Active (ICC) |
|  |  |  | L | H | Data Out | High Z | Read - Lower bits only | Active (ICC) |
|  |  |  | H | L | High Z | Data Out | Read - Upper bits only | Active (ICC) |
| L | X | L | L | L | Data In | Data In | Write - All bits | Active (ICC) |
|  |  |  | L | H | Data In | High Z | Write - Lower bits only | Active (ICC) |
|  |  |  | H | L | High Z | Data In | Write - Upper bits only | Active (ICC) |
| L | H | H | X | X | High Z | High Z | Selected, Outputs Disabled | Active (ICC) |
| L | X | X | H | H | High Z | High Z | Selected, Outputs Disabled | Active (ICC) |

## Ordering Information

| Speed <br> (ns) | Ordering Code | Package <br> Name | Package Type | Operating <br> Range |
| :---: | :--- | :---: | :--- | :--- |
| 10 | CY7C1020V33-10VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1020V33L-10VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1020V33-10ZC | Z44 | 44-Lead TSOP Type II | Commercial |
|  | CY7C1020V33L-10ZC | Z44 | 44-Lead TSOP Type II | Commercial |
|  | CY7C1020V33-12VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1020V33L-12VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1020V33-12ZC | Z44 | 44-Lead TSOP Type II | Commercial |
|  | CY7C1020V33L-12ZC | Z44 | 44-Lead TSOP Type II | Commercial |
|  | CY7C1020V33-15VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1020V33L-15VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
|  | CY7C1020V33-15ZC | Z44 | 44-Lead TSOP Type II | Commercial |
|  | CY7C1020V33L-15ZC | Z44 | 44-Lead TSOP Type II | Commercial |
|  | CY7C1020V33-15ZI | Z44 | 44-Lead TSOP Type II | Industrial |
| 20 | CY7C1020V33L-20ZC | Z44 | 44-Lead TSOP Type II | Commercial |

Document \#: 38-00543-B

## Package Diagrams

## 44-Lead (400-Mil) Molded SOJ V34




## 44-Pin TSOP II Z44

DIMENSIDN [N MM (INCH)
$\frac{\text { MAX }}{\text { MIN }}$
LEAD CIPLANARITY 0,004 [NCHES


